

Test Report issued under the responsibility of:

SAMSUNG

TEST REPORT IEC 62471 Photobiological safety of lamps and lamp systems	
Report Reference No.	18-03-01
Date of issue	2018-03-12
Total number of pages	
Testing Laboratory	SAMSUNG ELECTRONICS Co., Ltd.
Address	1, Samsung-ro, Giheung-gu, Yongin-si, Gyeonggi-do, 17113, Korea
Applicant's name	SAMSUNG ELECTRONICS Co., Ltd.
Address	129, Samsung-ro, Yeongtong-gu, Suwon-si, Gyeonggi-do, 16677, Korea
Test specification:	
Standard	IEC 62471:2006 (First Edition)
Test procedure	N/A
Non-standard test method	N/A
Test Report Form No.	IEC62471A
TRF Originator	VDE Testing and Certification Institute
Master TRF	Dated 2009-05
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This report is not valid as a CB Test Report unless signed by an approved CB Testing Laboratory and appended to a CB Test Certificate issued by an NCB in accordance with IECEE 02.	
Test item description	LED PKG
Trade Mark	SAMSUNG
Manufacturer	Same as Testing Laboratory
Model/Type reference	SPMWHD32AMD5XAP0S0
Ratings	DC 180 mA / 2,89 V

Testing procedure and testing location:	
<input type="checkbox"/> Testing Laboratory:	SAMSUNG ELECTRONICS Co., Ltd. (LED Biz.)
Testing location/ address	1, Samsung-ro, Giheung-gu, Yongin-si, Gyeonggi-do, 17113, Korea
<input type="checkbox"/> Associated Laboratory:	
Testing location/ address	
Tested by (name + signature)..... :	
Approved by (+ signature)	
<input type="checkbox"/> Testing procedure: TMP	
Tested by (name + signature)..... :	
Approved by (+ signature)	
Testing location/ address	
<input type="checkbox"/> Testing procedure: WMT	
Tested by (name + signature)..... :	
Witnessed by (+ signature)	
Approved by (+ signature)	
Testing location/ address	
<input type="checkbox"/> Testing procedure: SMT	
Tested by (name + signature)..... :	
Approved by (+ signature)	
Supervised by (+ signature)..... :	
Testing location/ address	
<input type="checkbox"/> Testing procedure: RMT	
Tested by (name + signature)..... :	
Approved by (+ signature)	
Supervised by (+ signature)..... :	
Testing location/ address	

Summary of testing:**Tests performed (name of test and test clause):**

- The sample was applied DC 180 mA following by applicant request.
- The sample was measured at 25°C.

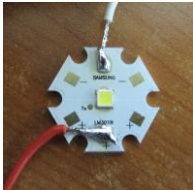
Testing location:

SAMSUNG ELECTRONICS Co., Ltd
1, Samsung-ro, Giheung-gu, Yongin-si,
Gyeonggi-do, 17113, Korea

Summary of compliance with National Differences:

The sample(s) tested complies with the requirements of IEC 62471:2006 and EN 62471:2008.
See Attachment at the end of this report for compliance with European Group Difference and National Differences.

Copy of marking plate:

Test item particulars	
Tested lamp	<input checked="" type="checkbox"/> continuous wave lamps <input type="checkbox"/> pulsed lamps
Tested lamp system	
Lamp classification group (IEC)	<input checked="" type="checkbox"/> exempt <input type="checkbox"/> risk 1 <input type="checkbox"/> risk 2 <input type="checkbox"/> risk 3
Lamp classification group (EN)	<input type="checkbox"/> exempt <input checked="" type="checkbox"/> risk 1 <input type="checkbox"/> risk 2 <input type="checkbox"/> risk 3
Lamp cap	
Bulb	
Rated of the lamp	See Page 1
Furthermore marking on the lamp	
Seasoning of lamps according IEC standard	
Used measurement instrument.....	
Temperature by measurement	24.0 - 25.0 °C
Information for safety use.....	Not required
Possible test case verdicts:	
– test case does not apply to the test object.....: N/A	
– test object does meet the requirement.....: P (Pass)	
– test object does not meet the requirement.....: F (Fail)	
Testing:	
Date of receipt of test item	2017-12-01
Date (s) of performance of tests	2017-12-01~2017-12-04
General remarks:	
The test results presented in this report relate only to the object tested.	
This report shall not be reproduced, except in full, without the written approval of the Issuing testing laboratory.	
"(See Enclosure #)" refers to additional information appended to the report.	
"(See appended table)" refers to a table appended to the report.	
Throughout this report a comma (point) is used as the decimal separator.	
List of test equipment must be kept on file and available for review.	
General product information:	
<ul style="list-style-type: none"> - PKG : LM301B - CCT : 6 500K - CRI : 80 - Flux rank : SL - Tested current : DC 180 mA - A photo of test sample. 	
	
Throughout this report a <input checked="" type="checkbox"/> comma / <input type="checkbox"/> point is used as the decimal separator.	